nexperia

Reliability Monitoring Results

Quarters: Q1/2021 to Q4/2021

Based on structural similarity

Supplie	er	User Part Number						
Nexperia B.V.		74AUP2G06GW						
Part De	escription: Dual inverter; o	ppen-drain						
Proc	ction Family: AUP cess family: C075 kage family: TSSOP							
JESD47	7 Test	Test Conditions	Duration	# Lots	# Quantity	# Rejects		
	TEST					see		
# 1	Pre- and Post-Stress Electrical Test	Tamb = 25 °C	N/A	see below	all parts	below		
# 2	PC Preconditioning	JESD22-A113 MSL 1	N/A	863	73980	0		
	HTOL EFR	JESD22-A108	48 hours					
# 5a	High Temperature	Tj = 150°C	or	219	38230	0		
	Operating Life Extrinsic	$V_{CCMAX} \leq V \leq 1.2 * V_{CCMAX}$	168 hours					
# 5b	HTOL IFR High Temperature	JESD22-A108 Ti = 150°C	≥500 hours	84	6277	0		
	Operating Life Intrinsic	$V_{CCMAX} \le V \le 1.2^* V_{CCMAX}$		01	5277	č		
# 7	TC Temperature Cycling	JESD22-A104 -65 °C to 150°C	≥500 cycles	478	37734	0		
# 9	uHAST / HAST unbiased or biased High Accelerated Stress Test	JESD22-A101 Tamb = 130 °C, RH = 85%, V = V _{CCMAX}	96 hours	462	36246	0		

Calculation of PPM, FIT and MTTF

Test considered for PPM calculation: High Temperature Operating LifeTest Extrinsic (HTOL EFR, Test # 5a above) Test considered for FIT and MTTF calculations: High Temperature Operating LifeTest Intrinsic(HTOL IFR, Test # 5b above)

Confidence level 60%, derated to 55 °C, activation energy 0.7 eV, test time 168 to 1000 hours

Product Family	Package Family	Quantity	Rejects	Extrinsic Failure Rate (PPM)	Intrinsic Failure Rate (FIT)	MTTF (hrs)
AUP	TSSOP	6277	0	24	0.7	1.5 E+09

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